



03-05-04

Express Mail No. EV 346 810 609 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Thibaut MAURICE et al.

Confirmation No. 7072

Application No.: 10/716,897

Group Art Unit: 1772

Filing Date: November 18, 2003

Examiner:

For: PREPARATION METHOD FOR
PROTECTING THE BACK SURFACE OF A WAFER
AND BACK SURFACE PROTECTED WAFER

Attorney Docket No.: 4717-12000

INFORMATION DISCLOSURE STATEMENTCommissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a PTO form 1449 which lists nine (9) references for the Examiner's review and consideration. These references were cited in the European search report and a copy is enclosed.

These references are listed on the enclosed Form PTO-1449. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee is believed to be due for the filing of this statement as it is being submitted prior to an initial office action for this application. Should any fees be required, however, please charge such fees to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

Allan A. Fanucci (Reg. No. 30,256)

WINSTON & STRAWN LLP
CUSTOMER NO. 28765
(212) 294-3311

Date:

33-04

Enclosures

NY:846914.1


REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)

ATTY. DOCKET NO.:

4717-12000

APPLICATION SERIAL NO.:

10/716,897

APPLICANT:

Thibaut MAURICE et al.

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	3,787,710	1/1974	Cunningham	317	101	
	AB	4,053,335	10/1977	Hu	148	174	
	AC	4,687,682	8/1987	Koze	437	238	
	AD	5,599,722	2/1997	Sugisaka et al.	437	21	
	AE	5,981,353	11/1999	Tsai	438	424	
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AG	EP 0531 018 A3	8/1992	Europe			X	
	AH	DE 198 44 418 A1 (w/English Abstract)	4/2000	Germany			X	
	AI	FR 2454697	11/1980	France				
	AJ	WO 02/41399 A2	5/2002	PCT			X	

OTHER REFERENCES *(Including Author, Title, Date, Pertinent Pages, Etc.)*

	AK	
	AL	
	AM	

EXAMINER**DATE CONSIDERED**

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with **MPPE 609**; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.